

Final datasheet

EconoDUAL™3 模块采用 CoolSiC™ Trench MOSFET 带有 PressFIT 压接管脚和温度检测 NTC

特性

- 电气特性
 - $V_{DSS} = 1200\text{ V}$
 - $I_{DN} = 500\text{ A} / I_{DRM} = 1000\text{ A}$
 - 集成温度传感器
 - 可以从下面链接寻找适合的英飞凌驱动 IC <https://www.infineon.com/gdfinder>
- 机械特性
 - 标准封装
 - PressFIT 压接技术
 - 绝缘的基板
 - 高功率密度
 - 直接冷却型基板



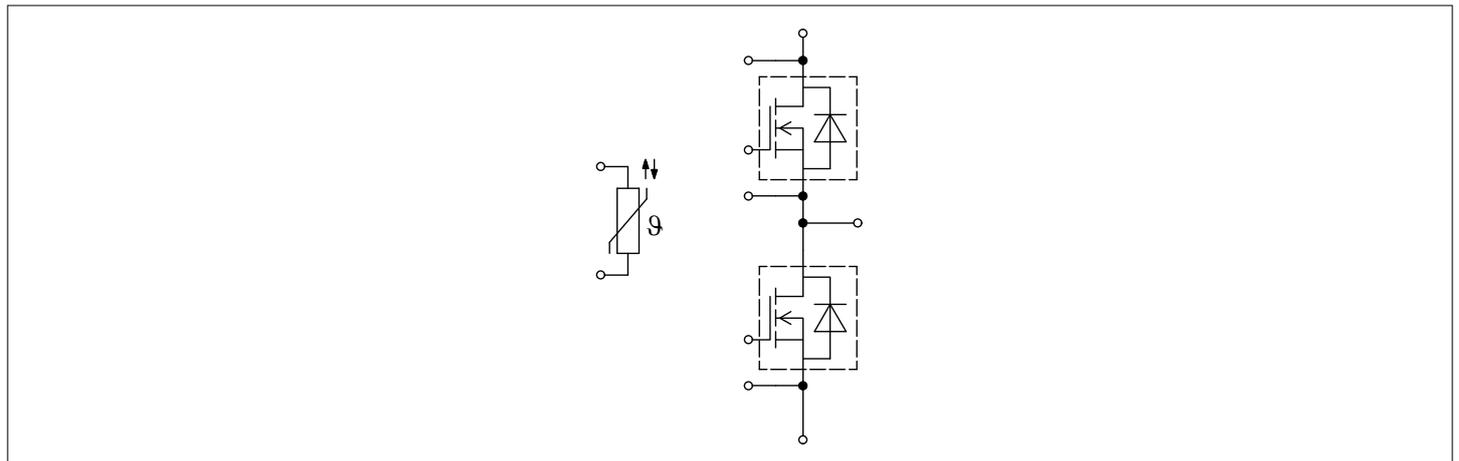
可选应用

- 建设用，商用及农用载具
- 风力发电机
- 电机传动
- UPS 系统
- 太阳能应用

产品认证

- 根据 IEC 60747、60749 和 60068 标准的相关测试，符合工业应用的要求。

描述



内容

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1 封装

1 封装

表 1 绝缘参数

特征参数	代号	标注或测试条件	数值		单位
			最小值	典型值	
绝缘测试电压	V_{ISOL}	RMS, $f = 50 \text{ Hz}$, $t = 1 \text{ min}$	3.4		kV
NTC 绝缘测试电压	$V_{ISOL(NTC)}$	RMS, $f = 50 \text{ Hz}$, $t = 1 \text{ min}$	3.4		kV
模块基板材料			Cu		
内部绝缘		基本绝缘 (class 1, IEC 61140)	Al_2O_3		
爬电距离	$d_{Creep \text{ nom}}$	端子到基板, nom.	> 15		mm
爬电距离	$d_{Creep \text{ min}}$	端子到基板, min.	14.7		mm
爬电距离	$d_{Creep \text{ nom}}$	端子至端子, nom.	> 19.3		mm
爬电距离	$d_{Creep \text{ min}}$	端子至端子, min.	19.3		mm
电气间隙	$d_{Clear \text{ nom}}$	端子到基板, nom.	> 12.5		mm
电气间隙	$d_{Clear \text{ min}}$	端子到基板, min.	12.5		mm
电气间隙	$d_{Clear \text{ nom}}$	端子至端子, nom.	> 10		mm
电气间隙	$d_{Clear \text{ min}}$	端子至端子, min.	9.6		mm
相对电痕指数	CTI		> 200		
相对温度指数 (电)	RTI	封装	140		°C

表 2 特征值

特征参数	代号	标注或测试条件	数值			单位
			最小值	典型值	最大值	
冷却回路的压降	Δp	$\Delta V/\Delta t = 10.0 \text{ dm}^3/\text{min}$, 50% water / 50% ethylenglycol, $T_F = 60 \text{ °C}$		65		mbar
冷却回路的最大压力	p				3	bar
杂散电感, 模块	L_{sCE}			20		nH
模块引线电阻, 端子-芯片	$R_{CC'+EE'}$	$T_F = 25 \text{ °C}$, 每个开关		0.8		mΩ
储存温度	T_{stg}		-40		125	°C
模块安装的安装扭距	M	根据相应的应用手册进行安装	M5, 螺丝	3	6	Nm
端子安装扭矩	M	根据相应的应用手册进行安装	M6, 螺丝	3	6	Nm
重量	G			345		g

2 MOSFET, T1 / T2

表 3 最大标定值

特征参数	代号	标注或测试条件		数值	单位
漏源极电压	V_{DSS}		$T_{vj} = 25\text{ °C}$	1200	V
连续漏极直流电流	I_{DDC}	$T_{vj} = 175\text{ °C}, V_{GS} = 18\text{ V}$	$T_F = 50\text{ °C}$	500	A
漏极重复峰值电流	I_{DRM}	verified by design, t_p limited by T_{vjmax}		1000	A
栅-源瞬态最大电压	V_{GS}	$D < 0.01$		-10/23	V
栅-源稳态最大电压	V_{GS}			-7/20	V

表 4 推荐值

特征参数	代号	标注或测试条件	[ZH]Values	单位
通态栅极电压	$V_{GS(on)}$		15...18	V
断态栅极电压	$V_{GS(off)}$		-5...0	V

表 5 特征值

特征参数	代号	标注或测试条件	数值			单位	
			最小值	典型值	最大值		
漏源通态电阻	$R_{DS(on)}$	$I_D = 500\text{ A}$	$V_{GS} = 15\text{ V},$ $T_{vj} = 25\text{ °C}$		1.75		mΩ
			$V_{GS} = 18\text{ V},$ $T_{vj} = 25\text{ °C}$		1.46	1.91	
			$V_{GS} = 18\text{ V},$ $T_{vj} = 125\text{ °C}$		2.36		
			$V_{GS} = 18\text{ V},$ $T_{vj} = 175\text{ °C}$		3.13		
栅极阈值电压	$V_{GS(th)}$	$I_D = 224\text{ mA}, V_{DS} = V_{GS}, T_{vj} = 25\text{ °C},$ (tested after 1ms pulse at $V_{GS} = +20\text{ V}$)	3.45	4.3	5.15	V	
栅极电荷	Q_G	$V_{DD} = 800\text{ V}, V_{GS} = -3/18\text{ V}, T_{vj} = 25\text{ °C}$		1.6		μC	
内部栅极电阻	R_{Gint}	$T_{vj} = 25\text{ °C}$		0.9		Ω	
输入电容	C_{ISS}	$f = 100\text{ kHz}, V_{DS} = 800\text{ V},$ $V_{GS} = 0\text{ V}$		48.4		nF	
输出电容	C_{OSS}	$f = 100\text{ kHz}, V_{DS} = 800\text{ V},$ $V_{GS} = 0\text{ V}$		2.4		nF	
反向传输电容	C_{RSS}	$f = 100\text{ kHz}, V_{DS} = 800\text{ V},$ $V_{GS} = 0\text{ V}$		0.158		nF	
C_{OSS} 存储能量	E_{OSS}	$V_{DS} = 800\text{ V}, V_{GS} = -3/18\text{ V}, T_{vj} = 25\text{ °C}$		945		μJ	
漏源泄漏电流	I_{DSS}	$V_{DS} = 1200\text{ V}, V_{GS} = -3\text{ V}$		0.32	660	μA	

(待续)

表 5 (续) 特征值

特征参数	代号	标注或测试条件	数值			单位
			最小值	典型值	最大值	
栅极漏电流	I_{GSS}	$V_{DS} = 0 \text{ V}, T_{vj} = 25 \text{ }^\circ\text{C}$	$V_{GS} = 20 \text{ V}$		400	nA
开通延迟时间(感性负载)	$t_{d\ on}$	$I_D = 500 \text{ A}, R_{Gon} = 6.8 \text{ } \Omega, V_{DD} = 600 \text{ V}, V_{GS} = -3/18 \text{ V}, t_{dead} = 1000 \text{ ns}$	$T_{vj} = 25 \text{ }^\circ\text{C}$	156		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	172		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	182		
上升时间(感性负载)	t_r	$I_D = 500 \text{ A}, R_{Gon} = 6.8 \text{ } \Omega, V_{DD} = 600 \text{ V}, V_{GS} = -3/18 \text{ V}, t_{dead} = 1000 \text{ ns}$	$T_{vj} = 25 \text{ }^\circ\text{C}$	261		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	243		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	238		
关断延迟时间(感性负载)	$t_{d\ off}$	$I_D = 500 \text{ A}, R_{Goff} = 3.9 \text{ } \Omega, V_{DD} = 600 \text{ V}, V_{GS} = -3/18 \text{ V}$	$T_{vj} = 25 \text{ }^\circ\text{C}$	276		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	305		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	319		
下降时间(感性负载)	t_f	$I_D = 500 \text{ A}, R_{Goff} = 3.9 \text{ } \Omega, V_{DD} = 600 \text{ V}, V_{GS} = -3/18 \text{ V}$	$T_{vj} = 25 \text{ }^\circ\text{C}$	74		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	76		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	77		
开通损耗能量(每脉冲)	E_{on}	$I_D = 500 \text{ A}, V_{DD} = 600 \text{ V}, L_\sigma = 8 \text{ nH}, V_{GS} = -3/18 \text{ V}, R_{Gon} = 6.8 \text{ } \Omega, di/dt = 4.7 \text{ kA}/\mu\text{s} (T_{vj} = 175 \text{ }^\circ\text{C}), t_{dead} = 1000 \text{ ns}$	$T_{vj} = 25 \text{ }^\circ\text{C}$	40.2		mJ
			$T_{vj} = 125 \text{ }^\circ\text{C}$	38.3		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	39		
开通损耗能量(每脉冲), 优化条件下	$E_{on,o}$	$I_D = 500 \text{ A}, V_{DD} = 600 \text{ V}, L_\sigma = 8 \text{ nH}, V_{GS} = -3/18 \text{ V}, R_{Gon,o} = 2.4 \text{ } \Omega, di/dt = 9.3 \text{ kA}/\mu\text{s} (T_{vj} = 175 \text{ }^\circ\text{C}), t_{dead} = 200 \text{ ns}$	$T_{vj} = 25 \text{ }^\circ\text{C}$	16.8		mJ
			$T_{vj} = 125 \text{ }^\circ\text{C}$	17.1		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	18.1		
关断损耗能量(每脉冲)	E_{off}	$I_D = 500 \text{ A}, V_{DD} = 600 \text{ V}, L_\sigma = 8 \text{ nH}, V_{GS} = -3/18 \text{ V}, R_{Goff} = 3.9 \text{ } \Omega, dv/dt = 6.2 \text{ kV}/\mu\text{s} (T_{vj} = 175 \text{ }^\circ\text{C})$	$T_{vj} = 25 \text{ }^\circ\text{C}$	20.4		mJ
			$T_{vj} = 125 \text{ }^\circ\text{C}$	21.6		
			$T_{vj} = 175 \text{ }^\circ\text{C}$	22.2		
结-冷媒热阻 ¹⁾	R_{thJF}	每个 MOSFET, $\Delta V/\Delta t = 10.0 \text{ dm}^3/\text{min}$, 冷却剂 = 50% water / 50% ethylenglycol, $T_F = 60 \text{ }^\circ\text{C}$		0.12		K/W
允许开关的温度范围	$T_{vj\ op}$			-40	175	$^\circ\text{C}$

1) Typical R_{thJF} value using the heat sink described in AN-2022-05

注: The selection of positive and negative gate-source voltages impacts losses and the long-term behavior of the MOSFET and body diode. The design guidelines described in Application Notes AN 2018-09 and AN 2021-13 must be considered to ensure sound operation of the device over the planned lifetime.

$T_{vj\ op} > 150^\circ\text{C}$ is allowed for operation at overload conditions for MOSFET and body diode. For detailed specifications, please refer to AN 2021-13.

3 Body diode (MOSFET, T1 / T2)

表 6 最大标定值

特征参数	代号	标注或测试条件	数值	单位
体二极管正向直流电流	I_{SD}	$T_{vj} = 175^\circ\text{C}$, $V_{GS} = -3\text{ V}$ $T_F = 25^\circ\text{C}$	295	A

表 7 特征值

特征参数	代号	标注或测试条件	数值			单位
			最小值	典型值	最大值	
正向电压	V_{SD}	$I_{SD} = 500\text{ A}$, $V_{GS} = -3\text{ V}$	$T_{vj} = 25^\circ\text{C}$	4.14	5.2	V
			$T_{vj} = 125^\circ\text{C}$	3.88		
			$T_{vj} = 175^\circ\text{C}$	3.78		
反向恢复峰值电流	I_{rrm}	$I_{SD} = 500\text{ A}$, $di_s/dt = 4.7\text{ kA}/\mu\text{s}$, $V_{DD} = 600\text{ V}$, $V_{GS} = -3\text{ V}$, $t_{dead} = 1000\text{ ns}$	$T_{vj} = 25^\circ\text{C}$	76		A
			$T_{vj} = 125^\circ\text{C}$	114		
			$T_{vj} = 175^\circ\text{C}$	148		
恢复电荷	Q_{rr}	$I_{SD} = 500\text{ A}$, $di_s/dt = 4.7\text{ kA}/\mu\text{s}$, $V_{DD} = 600\text{ V}$, $V_{GS} = -3\text{ V}$, $t_{dead} = 1000\text{ ns}$	$T_{vj} = 25^\circ\text{C}$	3.7		μC
			$T_{vj} = 125^\circ\text{C}$	4.9		
			$T_{vj} = 175^\circ\text{C}$	7		
反向恢复损耗 (每脉冲)	E_{rec}	$I_{SD} = 500\text{ A}$, $di_s/dt = 4.7\text{ kA}/\mu\text{s}$ ($T_{vj} = 175^\circ\text{C}$), $V_{DD} = 600\text{ V}$, $V_{GS} = -3\text{ V}$, $t_{dead} = 1000\text{ ns}$	$T_{vj} = 25^\circ\text{C}$	0.12		mJ
			$T_{vj} = 125^\circ\text{C}$	0.37		
			$T_{vj} = 175^\circ\text{C}$	0.67		
反向恢复损耗 (每脉冲), 优化条件下	$E_{rec,o}$	$I_{SD} = 500\text{ A}$, $di_s/dt = 9.3\text{ kA}/\mu\text{s}$ ($T_{vj} = 175^\circ\text{C}$), $V_{DD} = 600\text{ V}$, $V_{GS} = -3\text{ V}$, $t_{dead} = 200\text{ ns}$	$T_{vj} = 25^\circ\text{C}$	1.3		mJ
			$T_{vj} = 125^\circ\text{C}$	3.8		
			$T_{vj} = 175^\circ\text{C}$	5.3		

4 负温度系数热敏电阻

表 8 特征值

特征参数	代号	标注或测试条件	数值			单位
			最小值	典型值	最大值	
额定电阻值 (待续)	R_{25}	$T_{NTC} = 25^\circ\text{C}$		5		k Ω

表 8 (续) 特征值

特征参数	代号	标注或测试条件	数值			单位
			最小值	典型值	最大值	
R ₁₀₀ 偏差	$\Delta R/R$	$T_{NTC} = 100\text{ °C}, R_{100} = 493\ \Omega$	-5		5	%
耗散功率	P_{25}	$T_{NTC} = 25\text{ °C}$			20	mW
B-值	$B_{25/50}$	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298,15\text{ K}))]$		3375		K
B-值	$B_{25/80}$	$R_2 = R_{25} \exp[B_{25/80}(1/T_2 - 1/(298,15\text{ K}))]$		3411		K
B-值	$B_{25/100}$	$R_2 = R_{25} \exp[B_{25/100}(1/T_2 - 1/(298,15\text{ K}))]$		3433		K

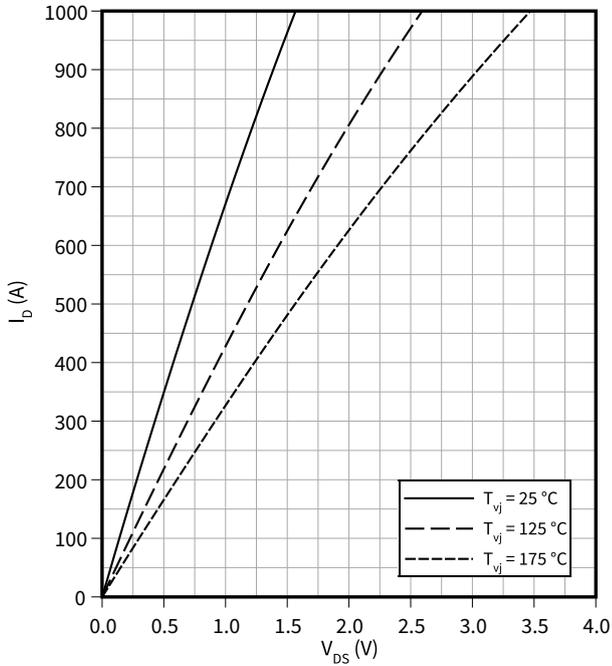
注: NTC 的具体参数分析请见 AN2009-10, 第 4 章

5 特征参数图表

输出特性 (典型), MOSFET, T1 / T2

$$I_D = f(V_{DS})$$

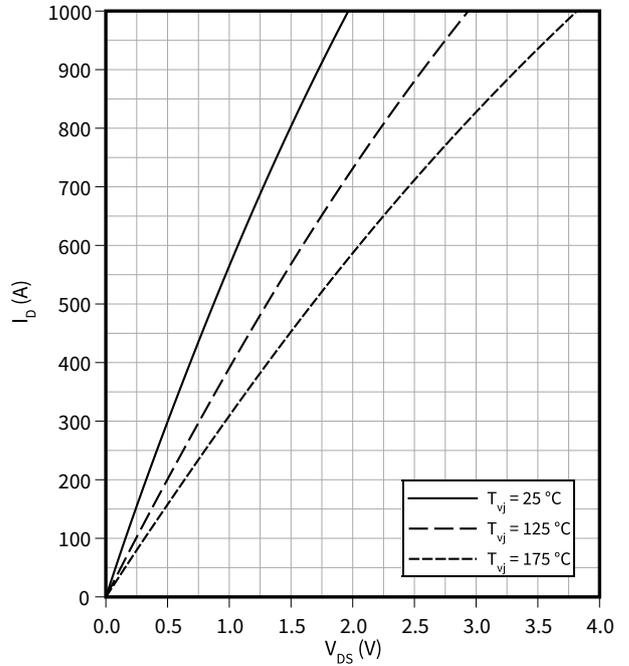
$$V_{GS} = 18\text{ V}$$



输出特性 (典型), MOSFET, T1 / T2

$$I_D = f(V_{DS})$$

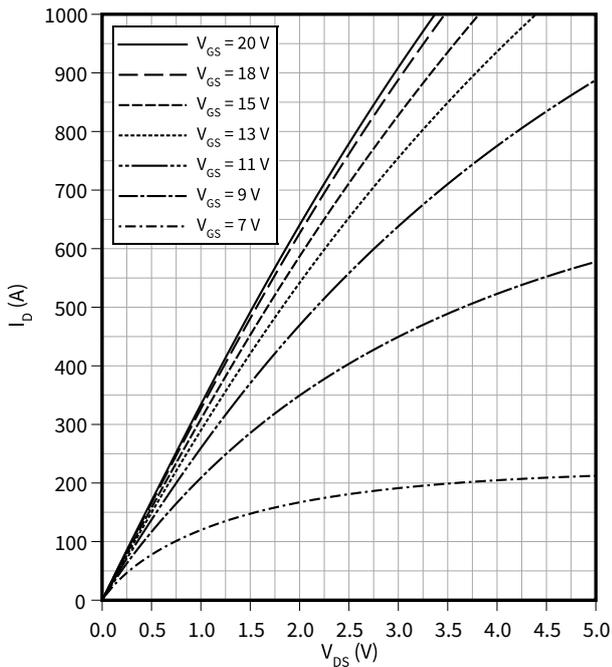
$$V_{GS} = 15\text{ V}$$



输出特性 (典型), MOSFET, T1 / T2

$$I_D = f(V_{DS})$$

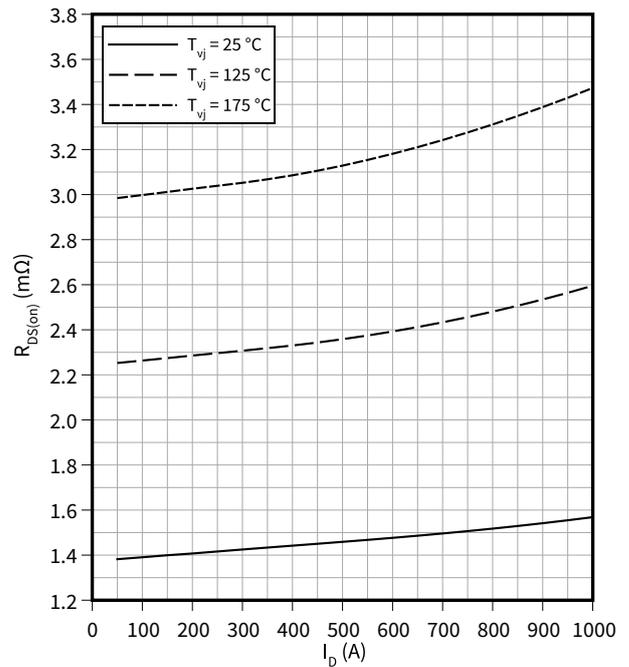
$$T_{vj} = 175^\circ\text{C}$$



漏源通态电阻 (典型), MOSFET, T1 / T2

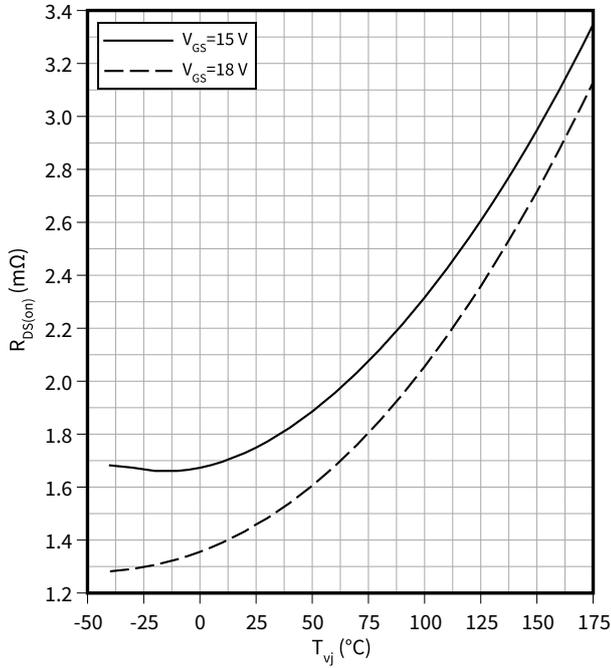
$$R_{DS(on)} = f(I_D)$$

$$V_{GS} = 18\text{ V}$$



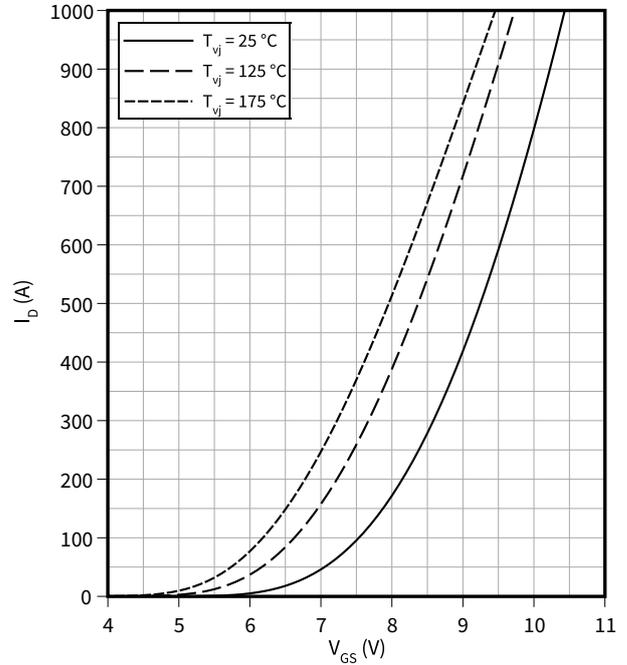
漏源通态电阻 (典型), MOSFET, T1 / T2

$R_{DS(on)} = f(T_{vj})$
 $I_D = 500 \text{ A}$



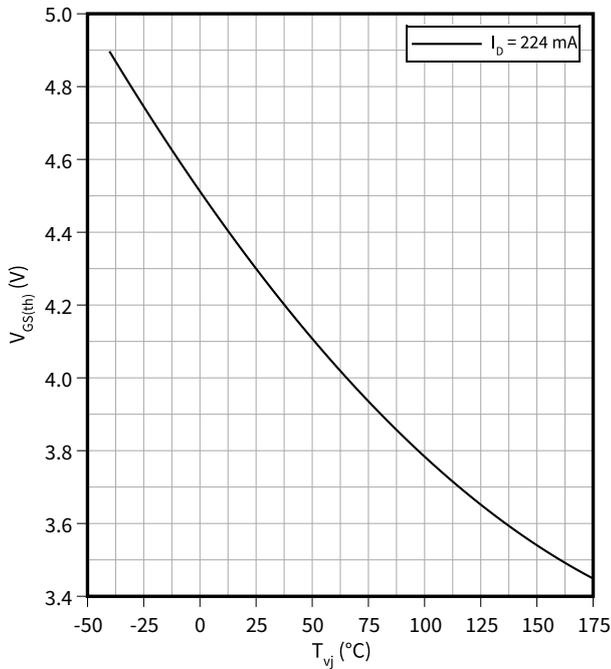
传输特性 (典型), MOSFET, T1 / T2

$I_D = f(V_{GS})$
 $V_{DS} = 20 \text{ V}$



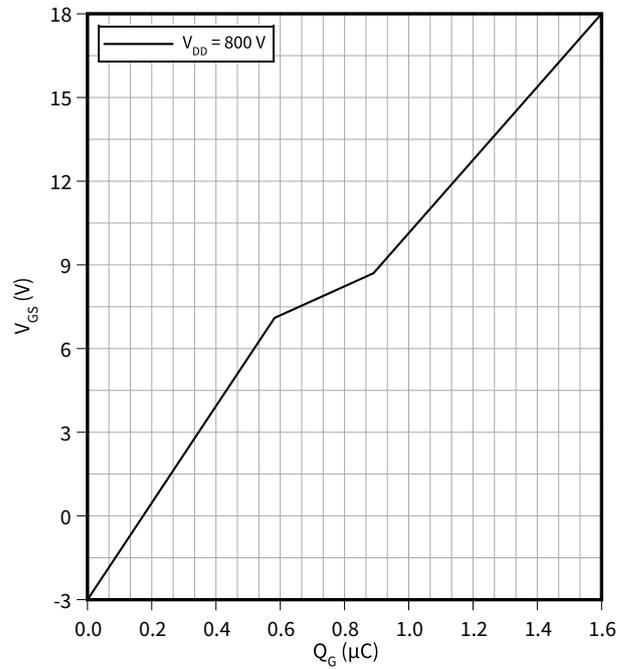
栅-源阈值电压 (典型), MOSFET, T1 / T2

$V_{GS(th)} = f(T_{vj})$
 $V_{GS} = V_{DS}$



栅极电荷特性 (典型), MOSFET, T1 / T2

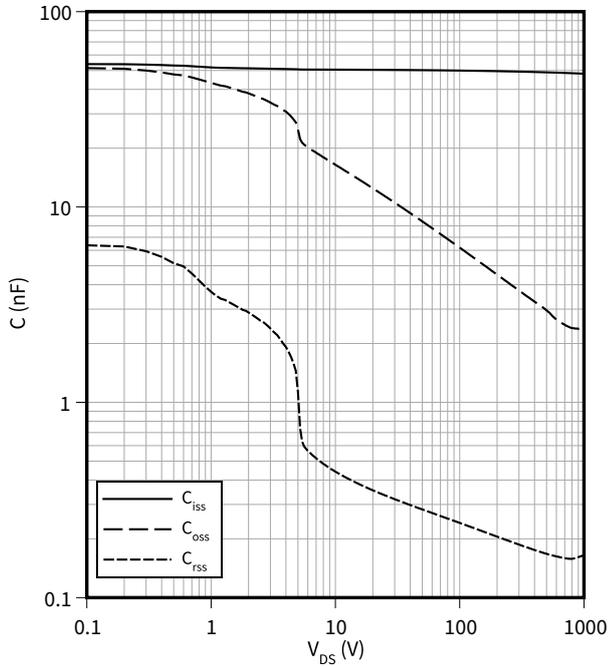
$V_{GS} = f(Q_G)$
 $I_D = 500 \text{ A}, T_{vj} = 25^\circ \text{C}$



电容特性 (典型), MOSFET, T1 / T2

$C = f(V_{DS})$

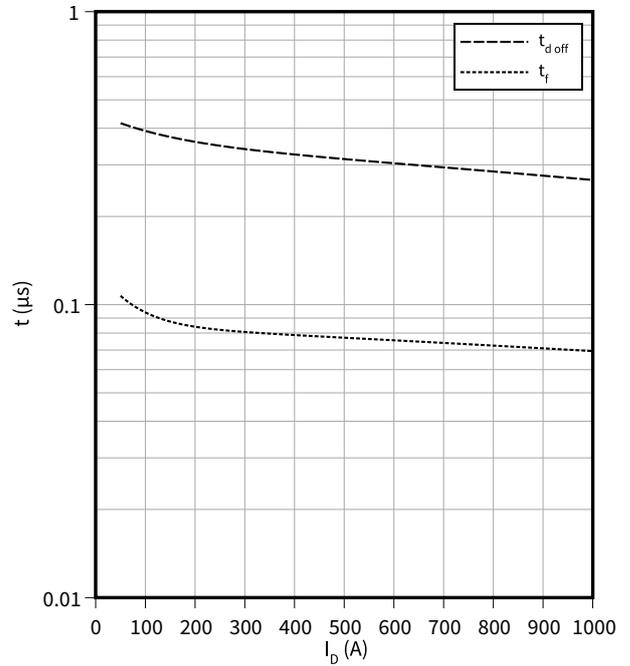
$T_{vj} = 25\text{ }^{\circ}\text{C}$, $V_{GS} = 0\text{ V}$, $f = 100\text{ kHz}$



开关时间 (典型), MOSFET, T1 / T2

$t = f(I_D)$

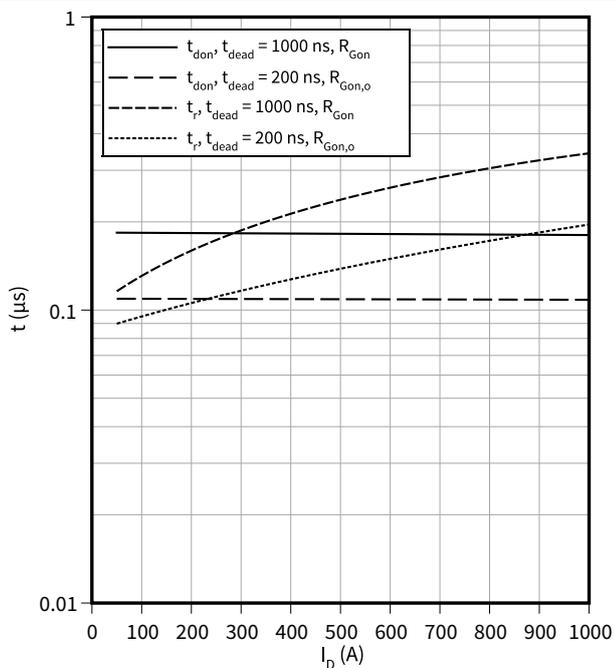
$R_{Goff} = 3.9\text{ }\Omega$, $V_{DD} = 600\text{ V}$, $T_{vj} = 175\text{ }^{\circ}\text{C}$, $V_{GS} = -3/18\text{ V}$



开关时间 (典型), MOSFET, T1 / T2

$t = f(I_D)$

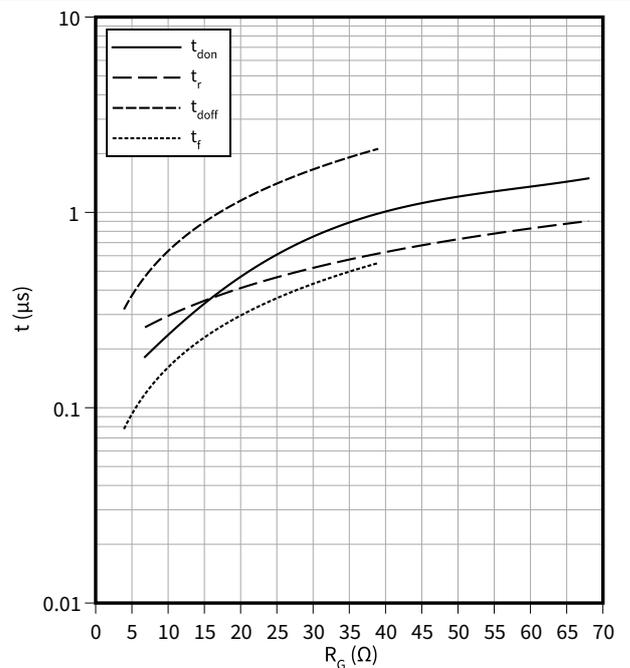
$V_{DD} = 600\text{ V}$, $R_{Gon} = 6.8\text{ }\Omega$, $R_{Gon,o} = 2.4\text{ }\Omega$, $T_{vj} = 175\text{ }^{\circ}\text{C}$, $V_{GS} = -3/18\text{ V}$



开关时间 (典型), MOSFET, T1 / T2

$t = f(R_G)$

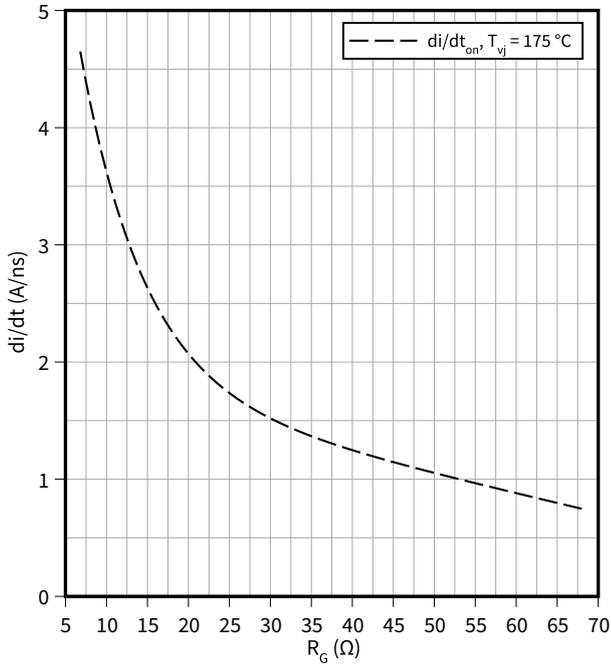
$V_{DD} = 600\text{ V}$, $t_{dead} = 1000\text{ ns}$, $I_D = 500\text{ A}$, $T_{vj} = 175\text{ }^{\circ}\text{C}$, $V_{GS} = -3/18\text{ V}$



电流变化斜率 (典型), MOSFET, T1 / T2

$di/dt = f(R_G)$

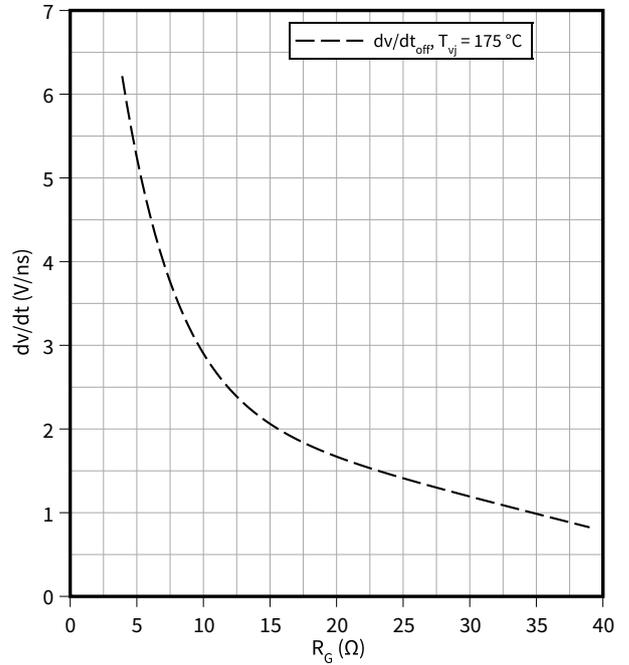
$V_{DD} = 600\text{ V}, I_D = 500\text{ A}, V_{GS} = -3/18\text{ V}$



电压变化斜率 (典型), MOSFET, T1 / T2

$dv/dt = f(R_G)$

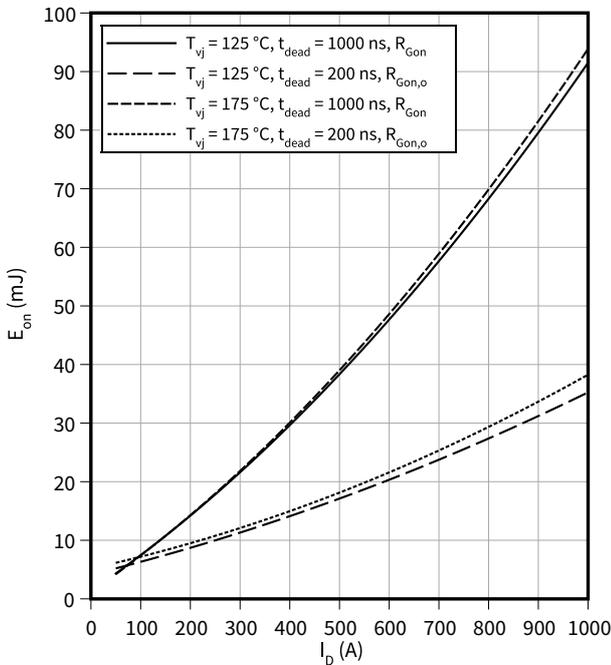
$V_{DD} = 600\text{ V}, I_D = 500\text{ A}, V_{GS} = -3/18\text{ V}$



开关损耗 (典型), MOSFET, T1 / T2

$E_{on} = f(I_D)$

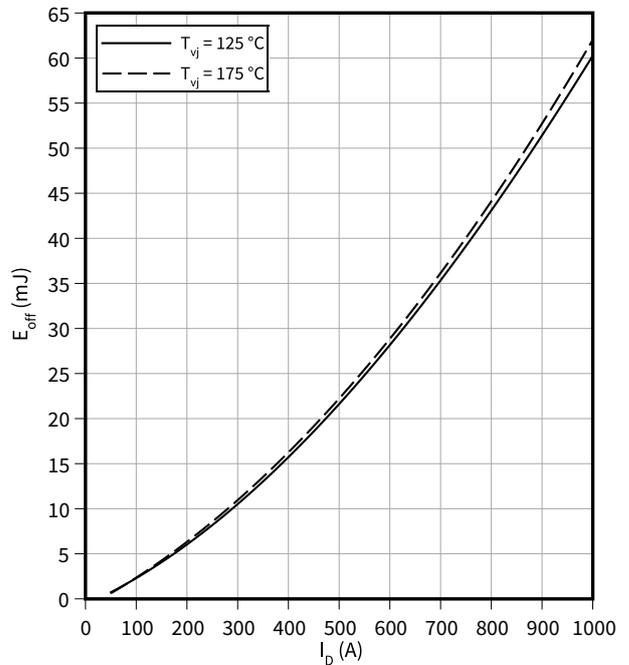
$V_{DD} = 600\text{ V}, R_{Gon} = 6.8\ \Omega, R_{Gon,o} = 2.4\ \Omega, V_{GS} = -3/18\text{ V}$



开关损耗 (典型), MOSFET, T1 / T2

$E_{off} = f(I_D)$

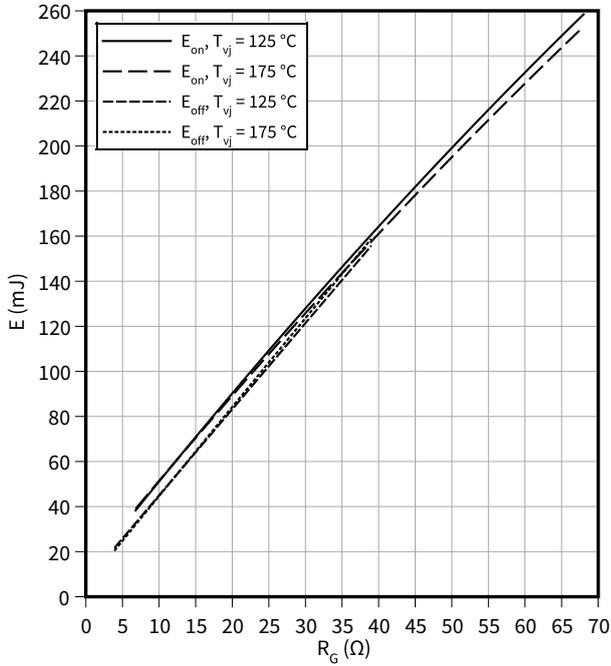
$R_{Goff} = 3.9\ \Omega, V_{DD} = 600\text{ V}, V_{GS} = -3/18\text{ V}$



开关损耗 (典型), MOSFET, T1 / T2

$E = f(R_G)$

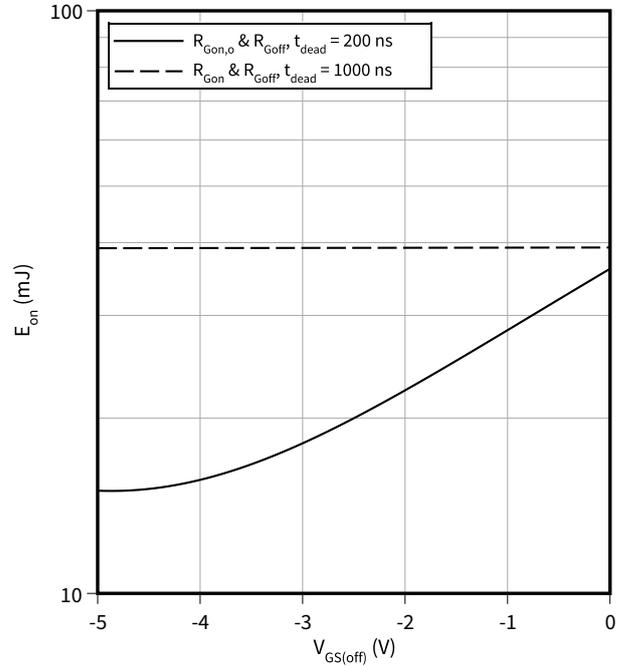
$V_{DD} = 600\text{ V}$, $t_{dead} = 1000\text{ ns}$, $I_D = 500\text{ A}$, $V_{GS} = -3/18\text{ V}$



开关损耗 (典型), MOSFET, T1 / T2

$E_{on} = f(V_{GS(off)})$

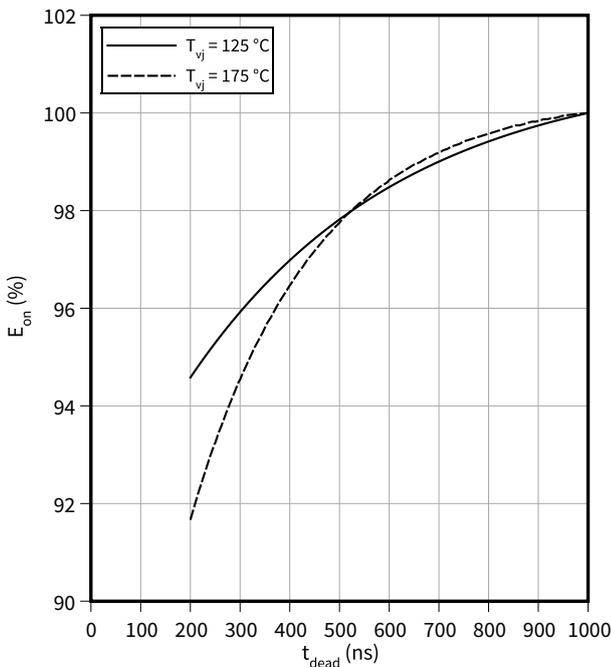
$R_{Goff} = 3.9\ \Omega$, $V_{DD} = 600\text{ V}$, $R_{Gon} = 6.8\ \Omega$, $V_{GS(on)} = 18\text{ V}$, $I_D = 500\text{ A}$, $R_{Gon,o} = 2.4\ \Omega$, $T_{vj} = 175\text{ °C}$



开关损耗 (典型), MOSFET, T1 / T2

$E_{on} = f(t_{dead})$

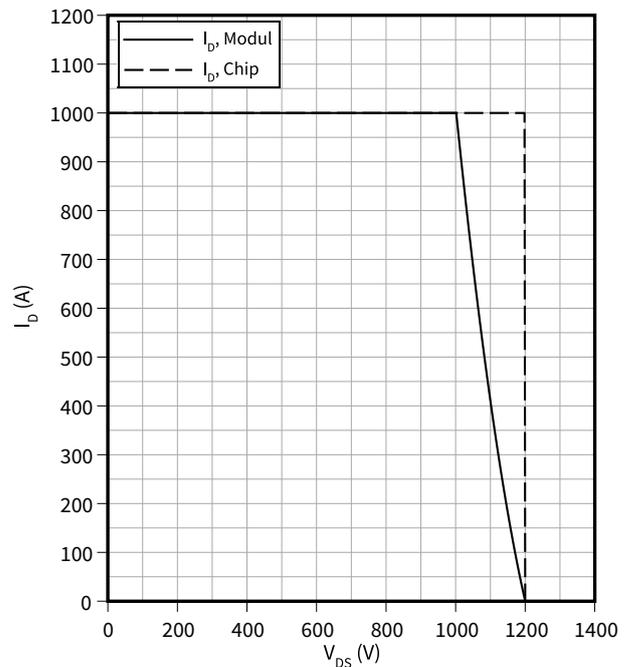
$R_{Gon} = 6.8\ \Omega$, $I_D = 500\text{ A}$, $V_{DD} = 600\text{ V}$, $V_{GS} = -3/18\text{ V}$



反偏安全工作区 (RBSOA), MOSFET, T1 / T2

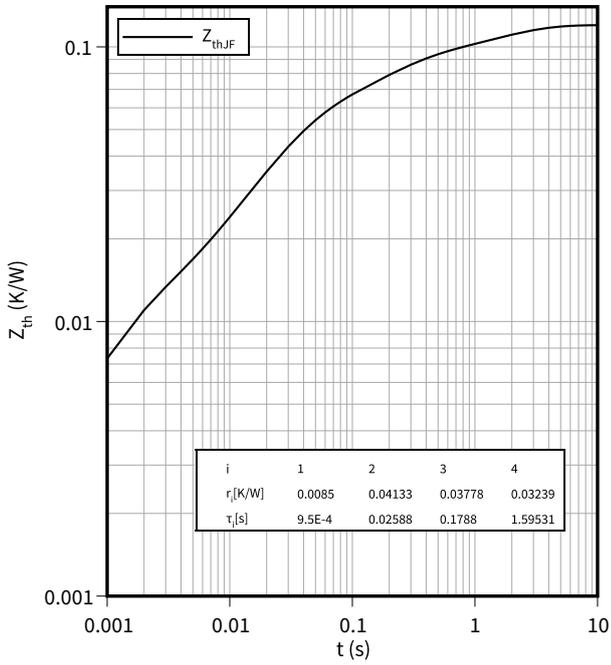
$I_D = f(V_{DS})$

$R_{Goff} = 3.9\ \Omega$, $T_{vj} = 175\text{ °C}$, $V_{GS} = -3/18\text{ V}$



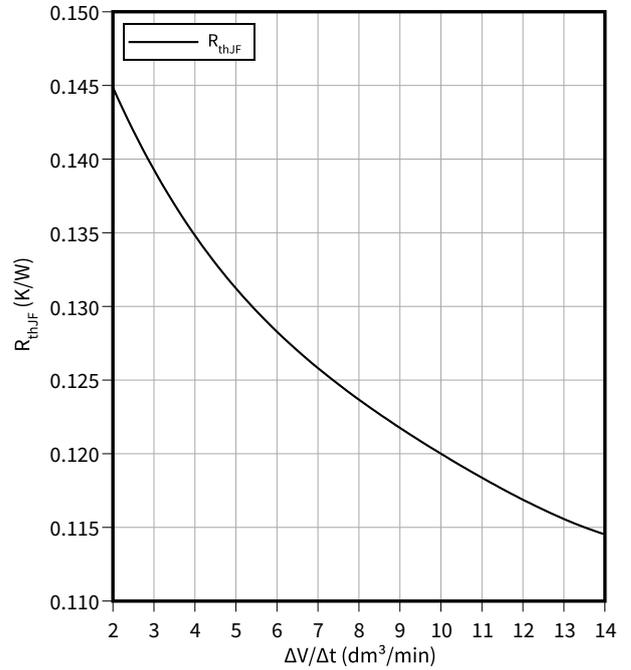
瞬态热阻抗, MOSFET, T1 / T2

$Z_{th} = f(t)$



热阻抗, MOSFET, T1 / T2

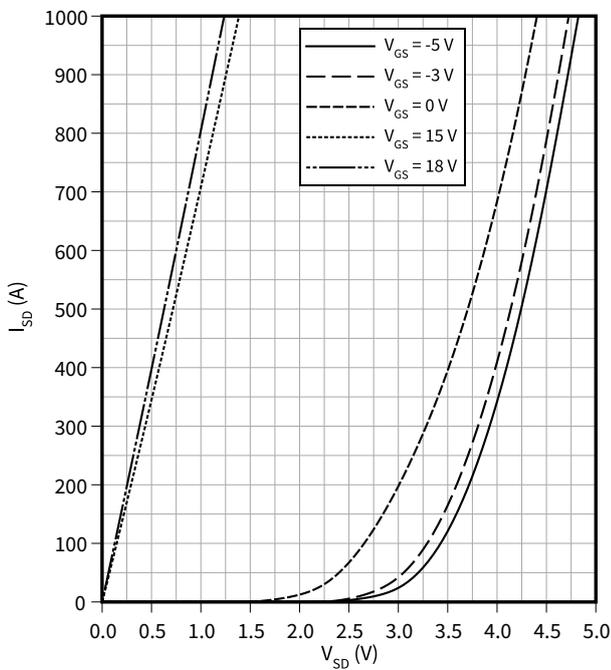
$R_{thJF} = f(\Delta V / \Delta t)$



正向特性 体二极管 (典型), MOSFET, T1 / T2

$I_{SD} = f(V_{SD})$

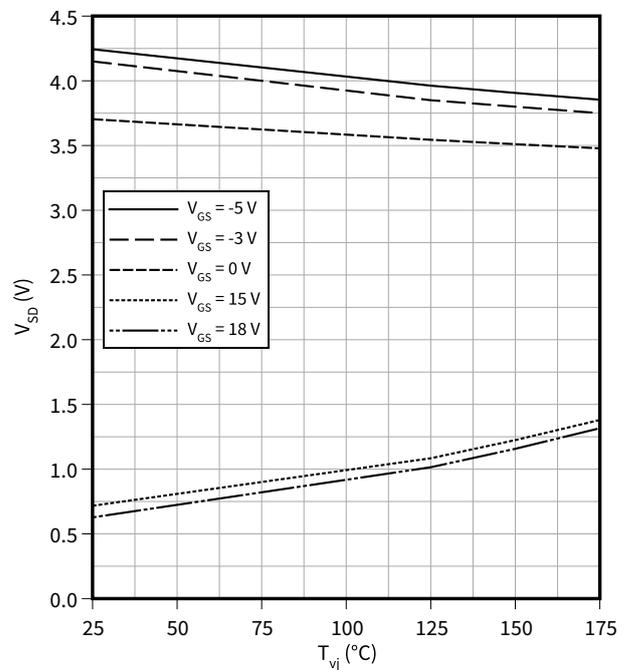
$T_{vj} = 25\text{ }^\circ\text{C}$



体二极管正向压降 (典型), MOSFET, T1 / T2

$V_{SD} = f(T_{vj})$

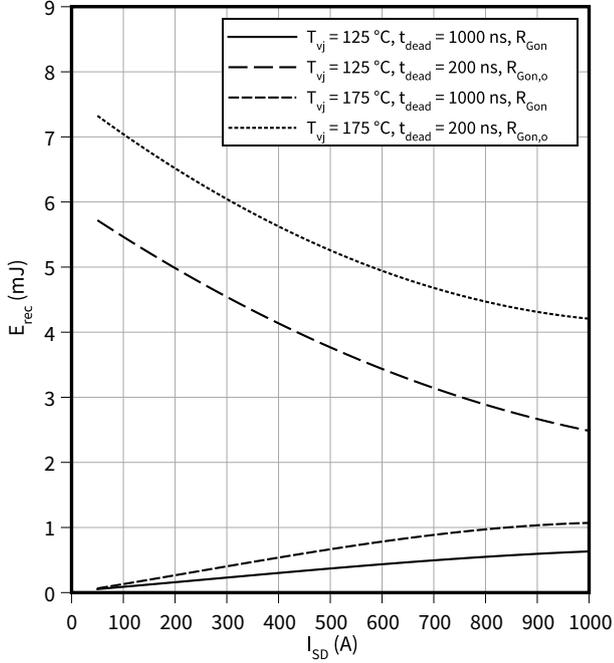
$I_{SD} = 500\text{ A}$



开关损耗 体二极管 (典型), MOSFET, T1 / T2

$E_{rec} = f(I_{SD})$

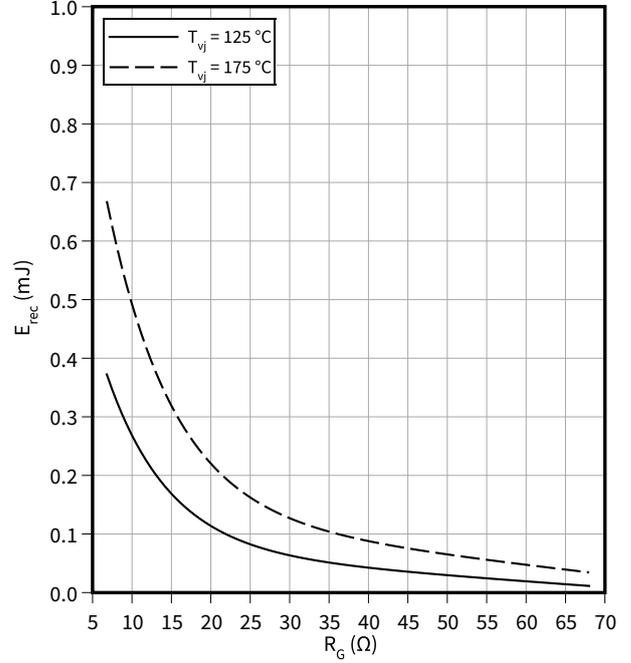
$R_{Gon} = 6.8 \Omega, R_{Gon,o} = 2.4 \Omega, V_{DD} = 600 V$



开关损耗 体二极管 (典型), MOSFET, T1 / T2

$E_{rec} = f(R_G)$

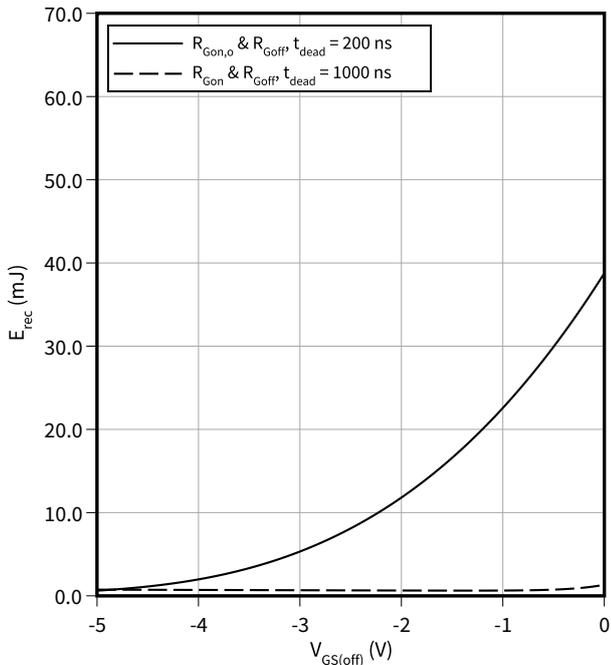
$t_{dead} = 1000 ns, I_{SD} = 500 A, V_{DD} = 600 V$



开关损耗 体二极管 (典型), MOSFET, T1 / T2

$E_{rec} = f(V_{GS(off)})$

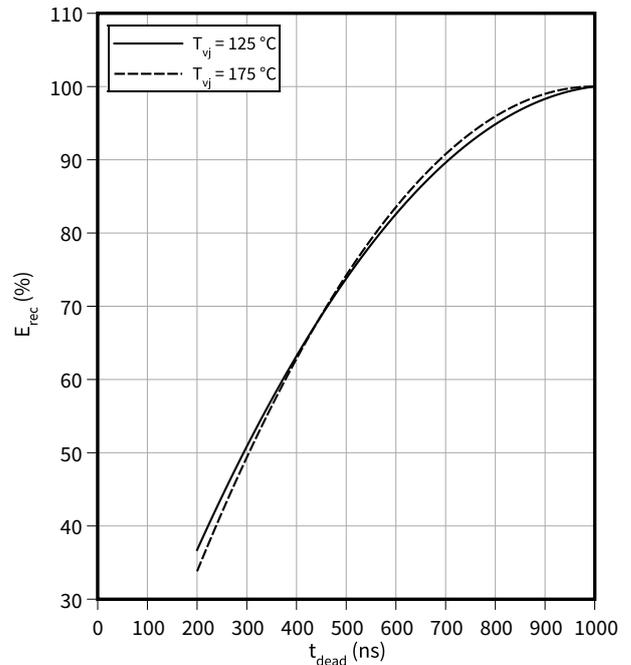
$R_{Goff} = 3.9 \Omega, R_{Gon} = 6.8 \Omega, V_{GS(on)} = 18 V, I_{SD} = 500 A, R_{Gon,o} = 2.4 \Omega, V_{DD} = 600 V, T_{vj} = 175 \text{ °C}$



开关损耗 体二极管 (典型), MOSFET, T1 / T2

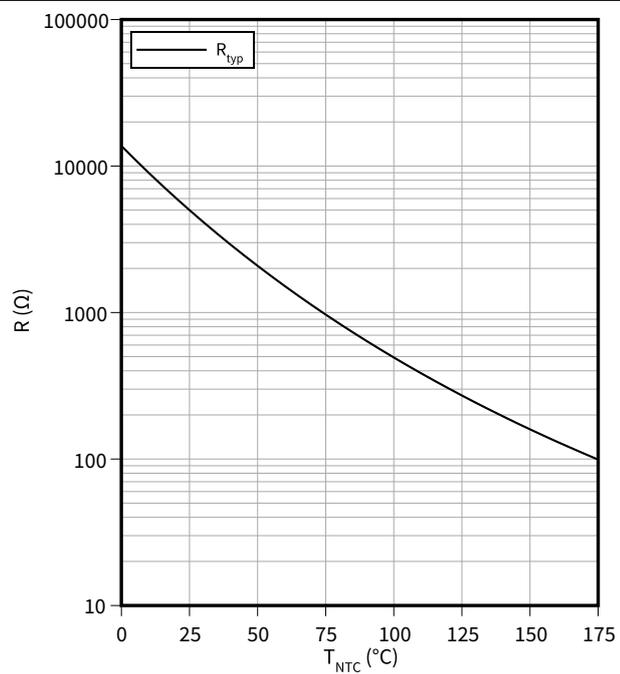
$E_{rec} = f(t_{dead})$

$R_{Gon} = 6.8 \Omega, I_D = 500 A, V_{DD} = 600 V, V_{GS} = -3/18 V$



温度特性, 负温度系数热敏电阻

$$R = f(T_{\text{NTC}})$$



7 封装尺寸

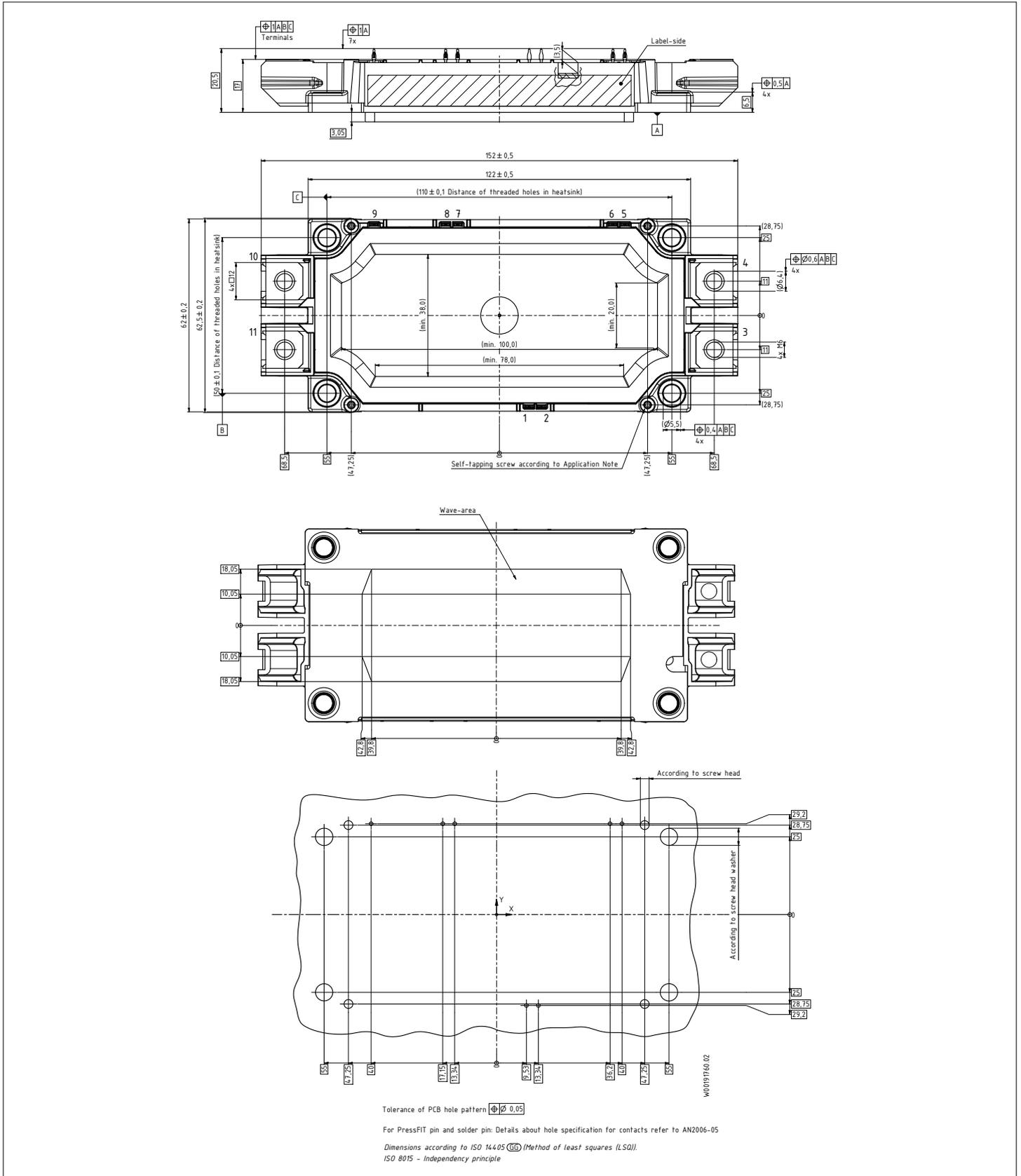


图 2

8 模块标签代码

Module label code			
Code format	Data Matrix	Barcode Code128	
Encoding	ASCII text	Code Set A	
Symbol size	16x16	23 digits	
Standard	IEC24720 and IEC16022	IEC8859-1	
Code content	<i>Content</i>	<i>Digit</i>	<i>Example</i>
	Module serial number	1 -5	71549
	Module material number	6 - 11	142846
	Production order number	12 - 19	55054991
	Date code (production year)	20 -21	15
	Date code (production week)	22 -23	30
Example	 		
	71549142846550549911530		71549142846550549911530

图 3

修订历史

修订版本	发布日期	变更说明
0.10	2024-12-02	Preliminary datasheet
1.00	2025-03-06	Final datasheet
1.10	2025-07-25	Final datasheet

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Edition 2025-07-25

Published by

Infineon Technologies AG

81726 Munich, Germany

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IFX-ABM306-003

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